

FORM PTO-1449

U.S. Department of Commerce  
Patent and Trademark OfficeAtty. Docket  
P29771Application No.  
10/576,023INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT

(Use several sheets if necessary)

Applicant  
Kimiaki TOSHIKIYOI.A. Filing Date  
April 17, 2006Group  
Not Yet Assigned

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	2006/	0 1 0 2 8 2 7	05/18/06	KASUGA et al.			
		5 7 4 2 4 3 3	04/21/98	SHIONO et al.			
		5 5 6 1 5 5 8	10/01/96	SHIONO et al.			
	2003/	0 1 6 8 6 7 9	09/11/03	NAKAI et al.			

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO
	2001	- 1 9 6 5 6 8	07/19/01	JAPAN				
	2000	- 0 3 9 5 0 3	02/08/00	JAPAN				
	5	- 2 5 1 6 7 3	09/28/93	JAPAN				
	2001	- 1 0 8 8 1 2	04/20/01	JAPAN			X	
	2001	- 3 1 8 2 1 7	11/16/01	JAPAN			X	
	7	- 1 1 3 9 0 7	05/02/95	JAPAN				
		0 6 4 9 0 3 7	04/19/95	E.P.O.				
	2003	- 2 2 9 5 5 3	08/15/03	JAPAN				
	2002	- 1 3 5 7 9 6	05/10/02	JAPAN			X	
	4	- 3 4 3 4 7 1	11/30/92	JAPAN			X	

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

1	English Language Abstract JP 2001-196568.
2	English Language Abstract JP 2000-039503.
3	English Language Abstract JP 5-251673.
4	D. W. PRATHER, "Design and application of subwavelength diffractive lenses for integration with infrared photodetectors," Opt. Eng. 38(5), pages 870-878 (May 1999; Society of Photo-Optical Instrumentation Engineers).
5	U.S. Patent Application No. 10/576,273.
6	English Language Abstract of JP 2001-108812.
7	English Language Abstract of JP 2001-318217.
8	English Language Abstract of JP 2002-135796.
9	English Language Abstract of JP 4-343471.

EXAMINER /Dwight Alex C Tejano/

DATE CONSIDERED 04/29/2009

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.